



Separation Scientific SA (Pty) Ltd

A new generation of **Hitachi SEM & TEM microscopes** to the SEA market.

Hitachi integrates ease of use, optimized imaging, and high-image quality, while maintaining the compact design of the well-established Hitachi Series of products.

Scanning Electron Microscope (SEM)



TM4000II / TM4000Plus II - The TM4000 Series features innovation and cutting-edge technologies which redefine the capabilities of a tabletop microscope.



The **FlexSEM 1000 VP-SEM** combines innovative technological features with an intuitive interface, to deliver adaptability and flexibility in a powerful, automated, lab-friendly package



Scanning Electron Microscope SU3800/SU3900: Hitachi High-Tech's scanning electron microscopes SU3800/SU3900 deliver both operability and expandability.



SU7000: The Next-Generation FE-SEM
The modern FE-SEM requires not only high performance but also a multitude of functionalities including wide-area observation, in-situ analysis, variable pressure, high-resolution imaging at low accelerating voltages, and simultaneous multi-signal collection.



The newly developed FIB-SEM system from Hitachi, the **NX9000** incorporates an optimized layout for true high-resolution serial sectioning to tackle the latest demands in 3D structural analysis and for TEM and 3DAP analyses.

Transmission Electron Microscope (TEM)

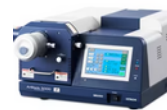


The **HT7800 RuliTEM** is a 120 kV transmission electron microscope (TEM) with multiple lens configurations, including a standard lens for unsurpassed high contrast and a class-leading HR lens for high resolution.



The **HF5000** builds on features from Hitachi HD-2700 dedicated STEM including Hitachi's own fully automated aberration corrector, symmetrical dual SDD EDX and Cs-corrected SE imaging. It also incorporates the advanced TEM/STEM technologies developed in the HF series.

Sample Prep



Ion Milling System ArBlade 5000
The most advanced broad ion beam system for producing exceptionally high-quality cross-section or flat-milling samples for electron microscopy.



The innovative **ZONETEM II** Desktop Sample Cleaner uses UV-based cleaning technology to minimize or eliminate hydrocarbon contamination for electron microscopy imaging. ZONE offers easy-to-use cleaning for pre-analysis sample preparation, ensuring the best possible data from your TEM samples.

Consumables

Consumables available for all models of SEM & TEM instruments.

Experience the new dimension of microscopy with us ... to find out more contact

Separation Scientific

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